

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/060,945	CARRICK ET AL.	
Examiner		Art Unit		Page 1 of 2
David S. Kim		2613		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,062,703 A	11-1991	Wong et al.	356/73.1
*	B	US-5,500,730 A	03-1996	Johnson, Robert W.	356/73.1
*	C	US-5,570,217 A	10-1996	Fleuren, Franciscus H.	398/13
*	D	US-5,982,530 A	11-1999	Akiyama et al.	359/279
*	E	US-6,111,676 A	08-2000	Lemus et al.	398/1
*	F	US-2002/0044314 A1	04-2002	Michishita, Yukio	359/110
*	G	US-6,856,723 B1	02-2005	Ito et al.	385/27
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sankawa, I. et al. "Fault location technique for in-service branched optical fiber networks." IEEE Photonics Technology Letters, Vol. 2, No. 10, October 1990: 766-768.
	V	Selvan, B. et al. "Network monitoring for passively split optical fibre networks." IEE Colloquium on Optical Fibre Video, Audio and Data Systems (Digest No. 1997/038). 28 Jan 1997: 5/1-5/4.
	W	Verhoof, J. W. "New method of in-service fault localisation in passive optical subscriber loops." Electronics Letters, Vol. 28, No. 11, 21 May 1992: 1059-1061.
	X	Von Der Weid, J.P. et al. "On the characterization of optical fiber network components with optical frequency domain reflectometry." Journal of Lightwave Technology, Vol. 15, No. 7, July 1997: 1131-1141.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/060,945	CARRICK ET AL.
	Examiner	Art Unit
	David S. Kim	2613
		Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Von Der Weid, J.P. et al. "Return loss measurements of WDM filters with tunable coherent optical frequency-domain reflectometry." IEEE Photonics Technology Letters, Vol. 9, No. 11, November 1997:1508-1510.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.